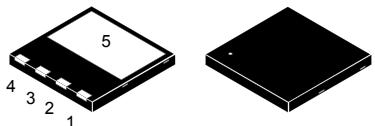
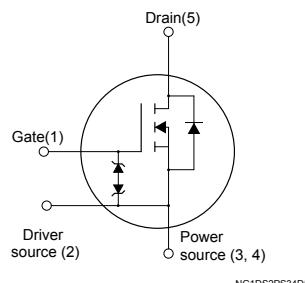


N-channel 600 V, 0.094 Ω typ., 25 A, MDmesh DM6 Power MOSFET in a PowerFLAT 8x8 HV package

Features



PowerFLAT 8x8 HV



Order code

Order code	V _{DS}	R _{DS(on)} max.	I _D
STL45N60DM6	600 V	0.110 Ω	25 A

- Fast-recovery body diode
- Lower R_{DS(on)} per area vs previous generation
- Low gate charge, input capacitance and resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

Applications

- Switching applications

Description

This high-voltage N-channel Power MOSFET is part of the MDmesh DM6 fast-recovery diode series. Compared with the previous MDmesh fast generation, DM6 combines very low recovery charge (Q_{rr}), recovery time (t_{rr}) and excellent improvement in R_{DS(on)} per area with one of the most effective switching behaviors available in the market for the most demanding high-efficiency bridge topologies and ZVS phase-shift converters.



Product status link

[STL45N60DM6](#)

Product summary

Order code	STL45N60DM6
Marking	45N60DM6
Package	PowerFLAT™ 8x8 HV
Packing	Tape and reel

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at $T_C = 25^\circ\text{C}$	25	A
	Drain current (continuous) at $T_C = 100^\circ\text{C}$	16	A
$I_{DM}^{(1)}$	Drain current (pulsed)	95	A
P_{TOT}	Total power dissipation at $T_C = 25^\circ\text{C}$	160	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	100	V/ns
$di/dt^{(2)}$	Peak diode recovery current slope	1000	A/ μs
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	100	V/ns
T_{stg}	Storage temperature range	-55 to 150	$^\circ\text{C}$
T_j	Operating junction temperature range		

1. Pulse width is limited by safe operating area.

2. $I_{SD} \leq 25 \text{ A}$, $V_{DS(\text{peak})} < V_{(BR)DSS}$, $V_{DD} = 400 \text{ V}$

3. $V_{DS} \leq 480 \text{ V}$

Table 2. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	0.78	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb	45	$^\circ\text{C}/\text{W}$

1. When mounted on FR-4 board of 1 inch², 2oz Cu.

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax})	6	A
E_{AS}	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50 \text{ V}$)	630	mJ

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}, T_C = 125^\circ\text{C}$ ⁽¹⁾			100	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 5	μA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3.25	4	4.75	V
$R_{\text{DS(on)}}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 12.5 \text{ A}$		0.094	0.110	Ω

1. Defined by design, not subject to production test.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	1920	-	pF
C_{oss}	Output capacitance		-	120	-	pF
C_{rss}	Reverse transfer capacitance		-	2	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ to } 480 \text{ V}, V_{GS} = 0 \text{ V}$	-	310	-	pF
R_G	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	1.5	-	Ω
Q_g	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 30 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 14. Gate charge test circuit)	-	44	-	nC
Q_{gs}	Gate-source charge		-	10	-	nC
Q_{gd}	Gate-drain charge		-	25	-	nC

1. $C_{oss \text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{on})}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 15 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	15	-	ns
t_r	Rise time		-	5.3	-	ns
$t_{d(\text{off})}$	Turn-off delay time	(see Figure 13. Switching times test circuit for resistive load and Figure 18. Switching time waveform)	-	50	-	ns
t_f	Fall time		-	7.3	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		25	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		95	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$, $I_{SD} = 25 \text{ A}$	-		1.5	V
t_{rr}	Reverse recovery time	$I_{SD} = 30 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$,	-	105		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 100 \text{ V}$ (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	0.48		μC
I_{RRM}	Reverse recovery current		-	9.3		A
t_{rr}	Reverse recovery time	$I_{SD} = 30 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$,	-	210		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 100 \text{ V}$, $T_j = 150 \text{ }^\circ\text{C}$ (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	1.95		μC
I_{RRM}	Reverse recovery current		-	18.6		A

1. Pulse width is limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5 %.

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

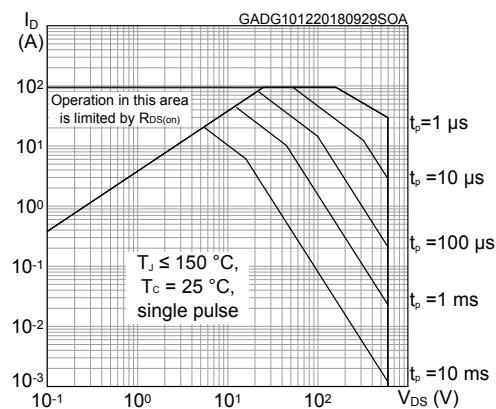


Figure 2. Thermal impedance

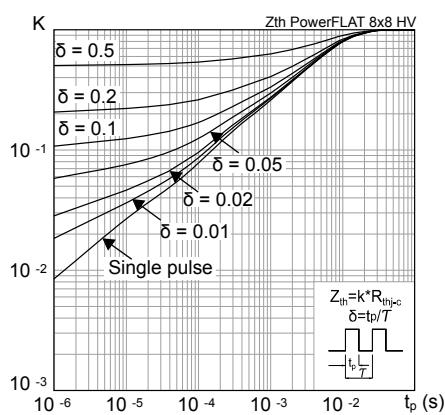


Figure 3. Output characteristics

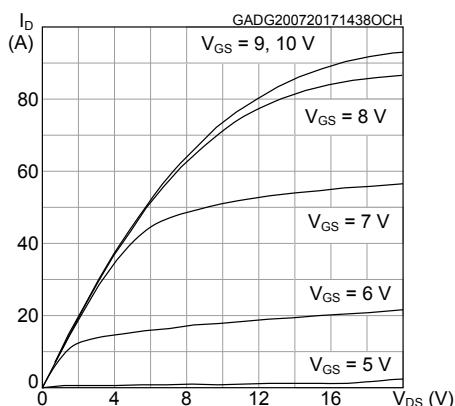


Figure 4. Transfer characteristics

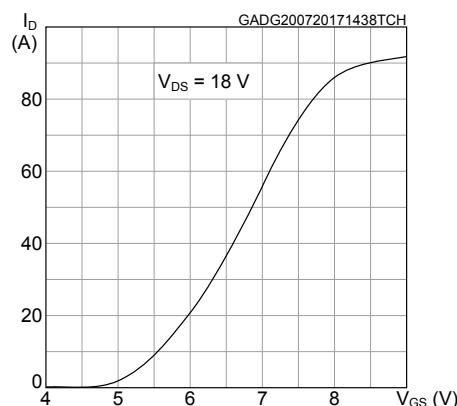


Figure 5. Gate charge vs gate-source voltage

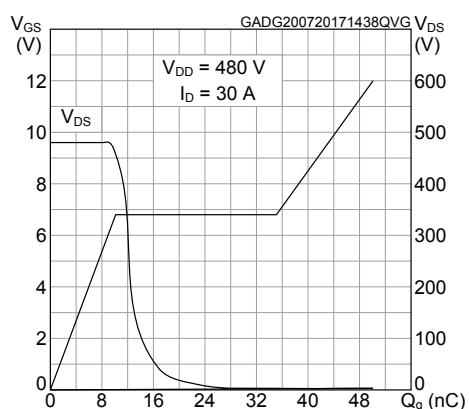


Figure 6. Static drain-source on-resistance

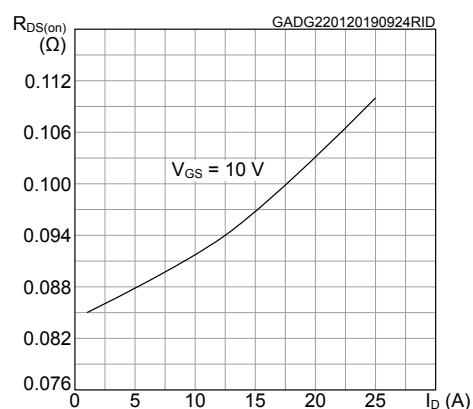
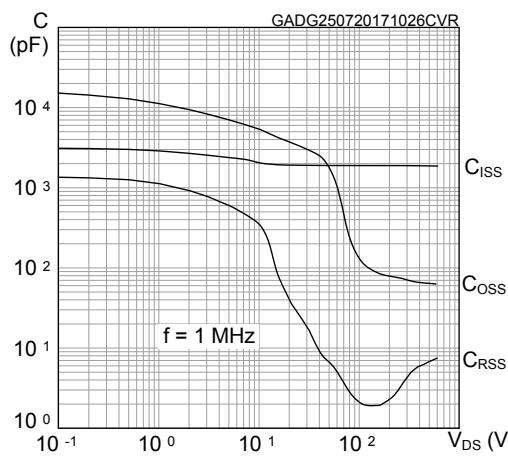
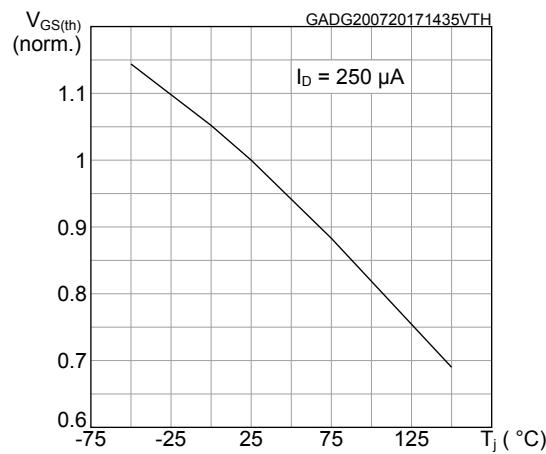
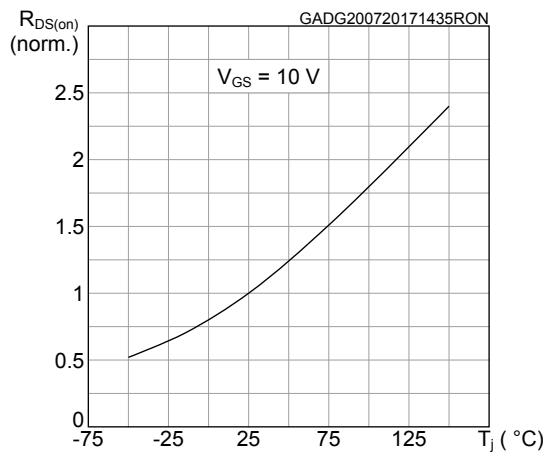
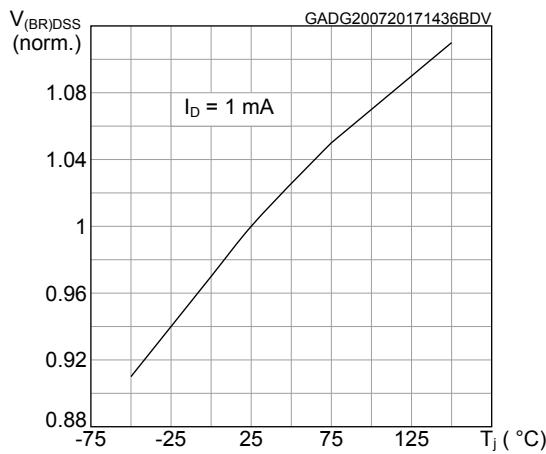
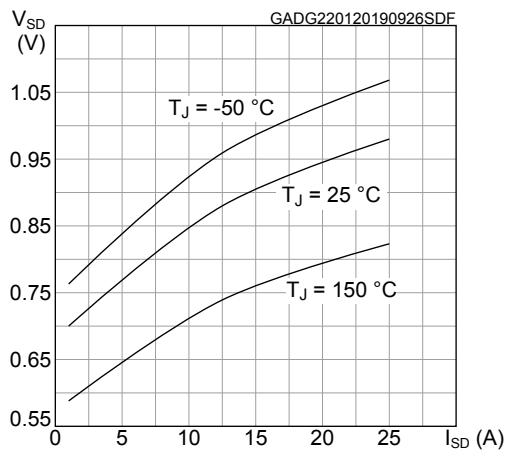
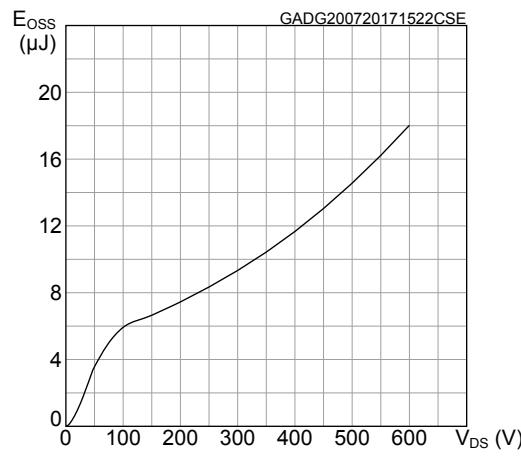
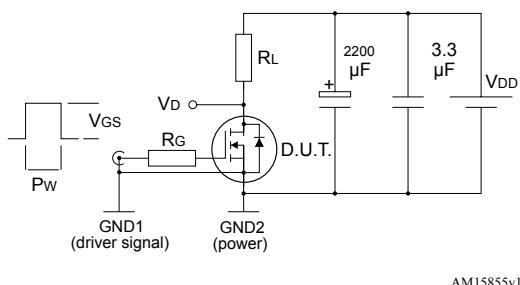


Figure 7. Capacitance variations

Figure 8. Normalized gate threshold voltage vs temperature

Figure 9. Normalized on-resistance vs temperature

Figure 10. Normalized V_(BR)DSS vs temperature

Figure 11. Source-drain diode forward characteristics

Figure 12. Output capacitance stored energy


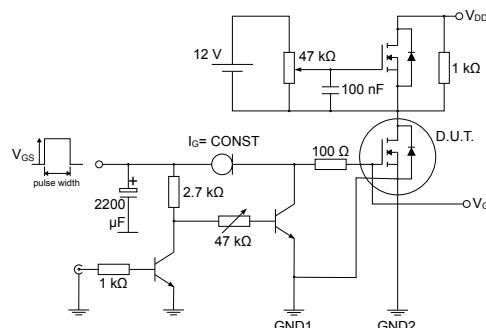
3 Test circuits

Figure 13. Switching times test circuit for resistive load



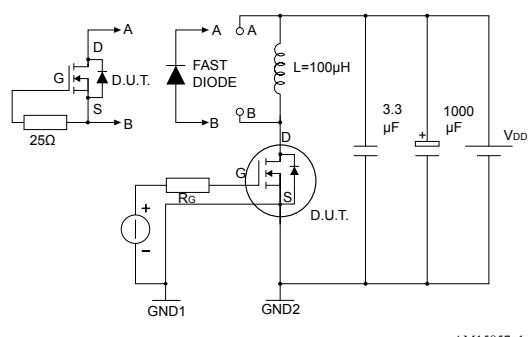
AM15855v1

Figure 14. Gate charge test circuit



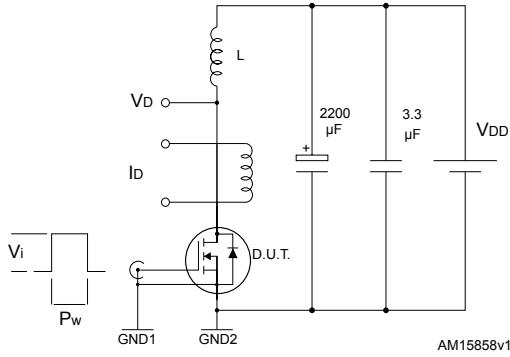
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Figure 15. Test circuit for inductive load switching and diode recovery times



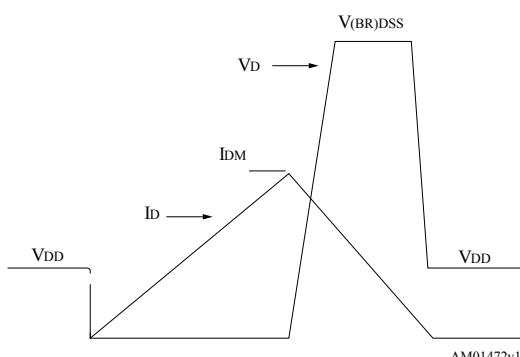
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Figure 16. Unclamped inductive load test circuit



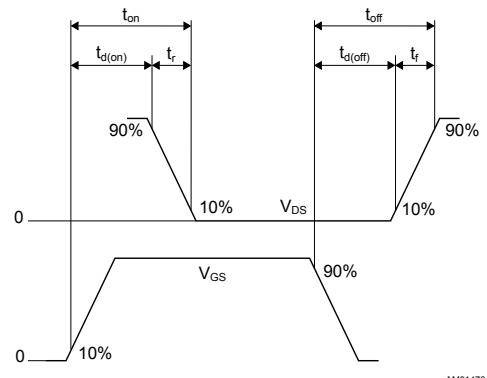
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Figure 17. Unclamped inductive waveform



AM01472v1

Figure 18. Switching time waveform



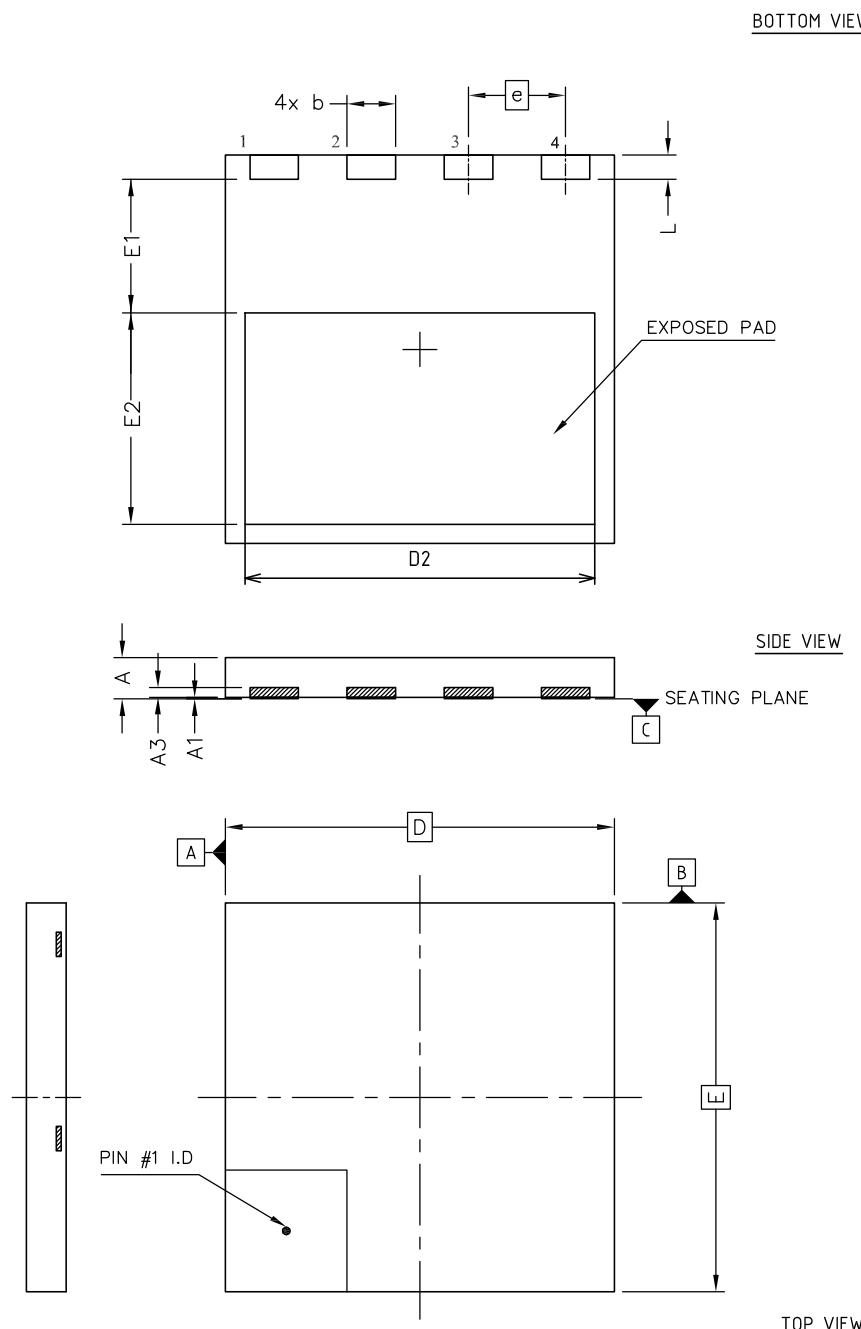
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4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 PowerFLAT 8x8 HV package information

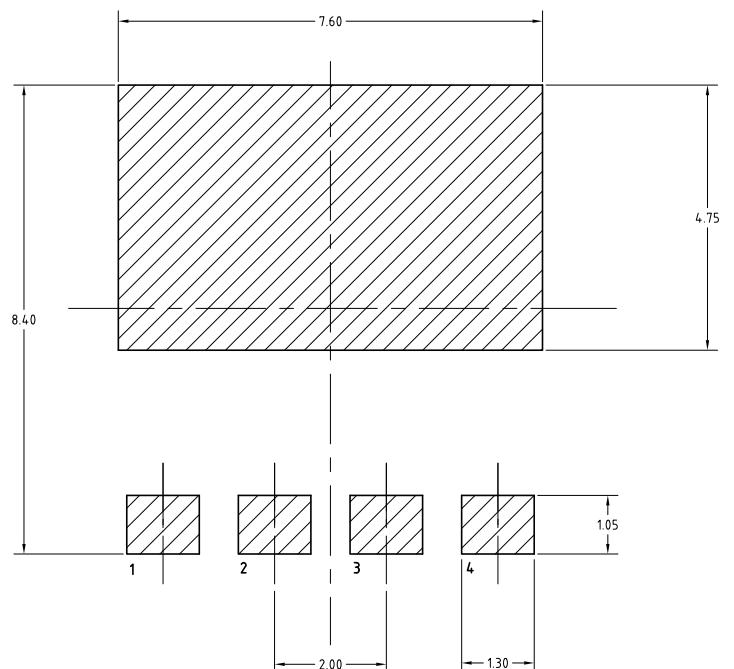
Figure 19. PowerFLAT 8x8 HV package outline



8222871_Rev_4

Table 8. PowerFLAT 8x8 HV mechanical data

Ref.	Dimensions (in mm)		
	Min.	Typ.	Max.
A	0.75	0.85	0.95
A1	0.00		0.05
A3	0.10	0.20	0.30
b	0.90	1.00	1.10
D	7.90	8.00	8.10
E	7.90	8.00	8.10
D2	7.10	7.20	7.30
E1	2.65	2.75	2.85
E2	4.25	4.35	4.45
e		2.00 BSC	
L	0.40	0.50	0.60

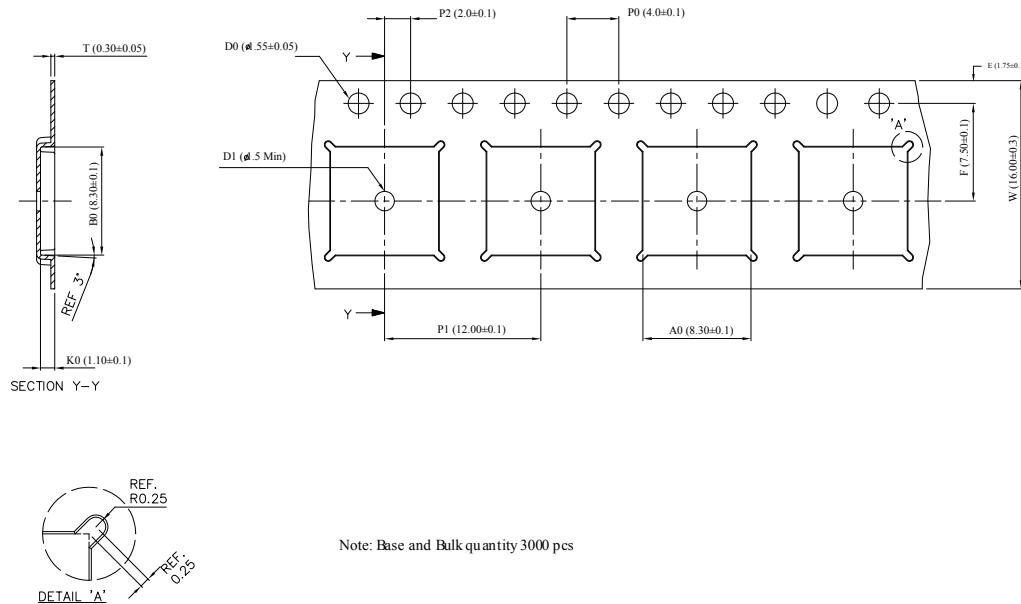
Figure 20. PowerFLAT 8x8 HV footprint

8222871_REV_4_footprint

Note: All dimensions are in millimeters.

4.2 PowerFLAT 8x8 HV packing information

Figure 21. PowerFLAT 8x8 HV tape



Note: All dimensions are in millimeters.

Figure 22. PowerFLAT 8x8 HV package orientation in carrier tape

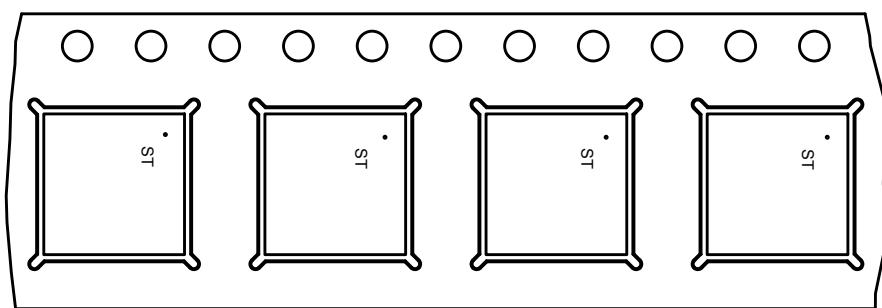
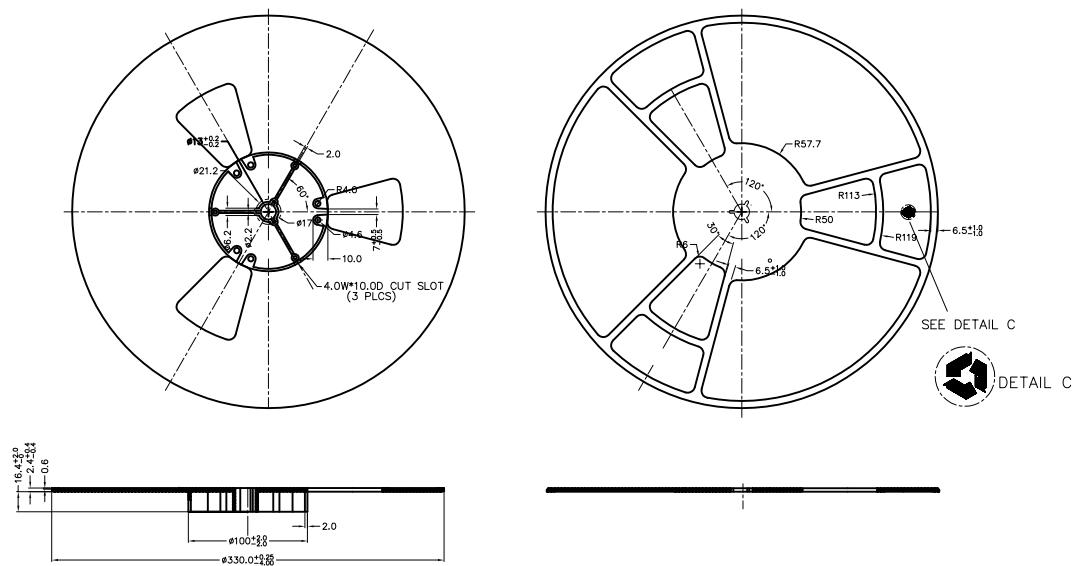


Figure 23. PowerFLAT 8x8 HV reel



8229819_Reel_revA

Note: All dimensions are in millimeters.

Revision history

Table 9. Document revision history

Date	Revision	Changes
27-May-2016	1	First release.
02-Aug-2017	2	Modified title and features in cover page. Updated <i>Section 1: "Electrical ratings" and Section 2: "Electrical characteristics"</i> . Added <i>Section 2.1: "Electrical characteristics (curves)"</i> . Minor text changes.
03-Jul-2018	3	Removed maturity status indication from cover page. Updated features on cover page. Minor text changes.
28-Jan-2019	4	Updated Table 1. Absolute maximum ratings, Table 4. On/off states and Table 7. Source drain diode. Updated Figure 1. Safe operating area, Figure 6. Static drain-source onresistance and Figure 11. Source-drain diode forward characteristics. Minor text changes.
21-Jul-2020	5	Updated Table 1. Absolute maximum ratings and Figure 22. PowerFLAT 8x8 HV package orientation in carrier tape.

Contents

1	Electrical ratings	2
2	Electrical characteristics.....	3
2.1	Electrical characteristics (curves)	5
3	Test circuits	7
4	Package information.....	8
4.1	PowerFLAT 8x8 HV package information	8
4.2	PowerFLAT 8x8 HV packing information	10
	Revision history	12

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